

**Notice of References Cited**

Application/Control No.

10/581,675

Applicant(s)/Patent Under  
Reexamination  
IINO ET AL.

Examiner

Khanh T. Nguyen

Art Unit

1796

Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0180088	12-2002	Hashiguchi et al.	264/102
*	B	US-2003/0191228	10-2003	Noguchi et al.	524/495
*	C	US-2002/0051903	05-2002	Masuko et al.	429/44
*	D	US-6,489,026	12-2002	Nishimura et al.	428/367
*	E	US-2002/0183438	12-2002	Amarasekera et al.	524/495
*	F	US-6,290,767	09-2001	Bergemann et al.	106/472
*	G	US-2006/0027790	02-2006	Arai et al.	252/500
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 2003-183461	07-2003	Japan	Yoshioka, Junichi	C08L 23/10
	O	JP 2003-268249	09-2003	Japan	Iino et al.	C08L 101/00
	P	JP 2000-348739	12-2000	Japan	Hayashi, Tatsuya	H01M 8/02
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.